

FORM PTO-1449 (MODIFIED)

INFORMATION DISCLOSURE STATEMENT
(Use several sheets if necessary)

ATTY. DOCKET NO.: 02008.071003	SERIAL NO.: 10/779,904
APPLICANT: Masahiro ISHIDA et al.	
FILING DATE: 02/17/2004	ART UNIT: 2136 OAL

U.S. PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	APPLICANT'S OR PATENTEE'S NAME
/OAL/	A1	5,790,565	08/04/1998	Sakaguchi

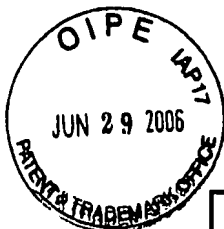
FOREIGN PATENT DOCUMENTS

EXAMINER INITIALS	REF	DOCUMENT NO.	DATE	COUNTRY	TRANSLATION	
					YES	NO
/OAL/	A2	DE 196 26 103 A1	01/02/1997	Germany		X
/OAL/	A3	DE 196 09 085 A1	09/12/1996	Germany		X
/OAL/	A4	10 - 239394	09/11/1998	Japan		X
/OAL/	A5	8 - 201486	08/09/1996	Japan		X

OTHER DOCUMENTS

EXAMINER INITIALS	REF	(Include Author, Title, Date, Pertinent Pages, etc.)
/OAL/	A6	German Office Action dated 01/23/2004 (7 pgs.)
/OAL/	A7	Patent Abstracts of Japan, Publication No. 10239394A dated 09/11/1998, 1 pg.
/OAL/	A8	Patent Abstracts of Japan, Publication No. 08201486A dated 08/09/1996, 1 pg.

EXAMINER: /Oscar Louie/ (08/21/2007)	DATE CONSIDERED: 08/21/2007
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PTO/SB/08a/b (07-05)

Approved for use through 07/31/2008. OMB 0651-0031
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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete If Known	
				Application Number	10/779,904-Conf. #9608
				Filing Date	February 17, 2004
				First Named Inventor	Masahiro Ishida
				Art Unit	2435 2136 OAL
				Examiner Name	Not Yet Assigned Oscar Louie
Sheet	1	of	2	Attorney Docket Number	02008/071003

OAL

U.S. PATENT DOCUMENTS					
Examiner Initials*	Cite No. ¹	Document Number	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number-Kind Code ² (if known)			

FOREIGN PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Foreign Patent Document		Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ²
		Country Code ³	Number ⁴ -Kind Code ⁵ (if known)				
/OAL/	BA	JP	4-244975	09-01-1992	Matsushita Electron Corp		
	BB	JP	6-258388	09-16-1994	Hitachi Ltd		
	BC	JP	8-201486	08-09-1996	Nec Corp		
	BD	JP	9-26981	01-28-1997	Fujitsu Ltd		
	BE	JP	9-54140	02-25-1997	Sharp Corp		
	BF	JP	9-80114	03-28-1997	Advantest Corp		
	BG	JP	10-125794	05-15-1998	NEC Corp		
	BH	JP	10-239394	09-11-1998	NEC Corp		
	BI	JP	11-174114	07-02-1999	Toshiba Corp		
	BJ	JP	60-165562	08-28-1985	Vladimirovsky et al.		
/OAL/	BK	JP	62-39780	02-20-1987	Mitsubishi Electric Corporation		

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NON PATENT LITERATURE DOCUMENTS					
Examiner Initials	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			T ²
/OAL/	CA	Patent Abstracts of Japan; Publication number: 04-244975; Date of Publication: 09/01/1992 (2 pages)			
	CB	Patent Abstracts of Japan; Publication number: 06-258388; Date of Publication: 09/16/1994 (2 pages)			
	CC	Patent Abstracts of Japan; Publication number: 08-201486; Date of Publication: 08/09/1996 (2 pages)			
	CD	Patent Abstracts of Japan; Publication number: 09-026981; Date of Publication: 01/28/1997 (2 pages)			
	CE	Patent Abstracts of Japan; Publication number: 09-054140; Date of Publication: 02/25/1997 (2 pages)			
	CF	Patent Abstracts of Japan; Publication number: 09-080114; Date of Publication: 03/28/1997 (2 pages)			
	CG	Patent Abstracts of Japan; Publication number: 10-125794; Date of Publication: 05/15/1998 (2 pages)			
	CH	Patent Abstracts of Japan; Publication number: 10-239394; Date of Publication: 09/11/1998 (2 pages)			
/OAL/	CI	Patent Abstracts of Japan; Publication number: 11-174114; Date of Publication: 07/02/1999 (2 pages)			
Examiner Signature	/Oscar Louie/ (08/21/2007)			Date Considered	08/21/2007



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Substitute for form 1449A/B/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (Use as many sheets as necessary)				Complete if Known	
				Application Number	10/779,904-Conf. #9608
				Filing Date	February 17, 2004
				First Named Inventor	Masahiro Ishida
				Art Unit	2133
				Examiner Name	Not Yet Assigned
Sheet	2	of	2	Attorney Docket Number	02008/071003

		pages)	
/OAL/	CJ	Patent Abstracts of Japan; Publication number: 11-174114; Date of Publication: 07/02/1999 (2 pages)	
/OAL/	CK	"Transient Power Supply Current Testing of Digital CMOS Circuits"; Rafic Z. Makki et al.; International Test Conference; Paper 38.1; IEEE; 1995; pp. 892-901	
/OAL/	CL	"Defect Detection with Transient Current Testing and its Potential for Deep Sub-micron CMOS ICs"; Manoj Sachdev et al; International Test Conference; IEEE 1998; Paper 8.4; pp. 204-213	
/OAL/	CM	Translation of Japanese Office Action dated April 4, 2006 (2 pages)	

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¹Applicant's unique citation designation number (optional). ²Applicant is to place a check mark here if English language Translation is attached.

Examiner Signature	/Oscar Louie/ (08/21/2007)	Date Considered	08/21/2007
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